

HQ:NSC35/No Al

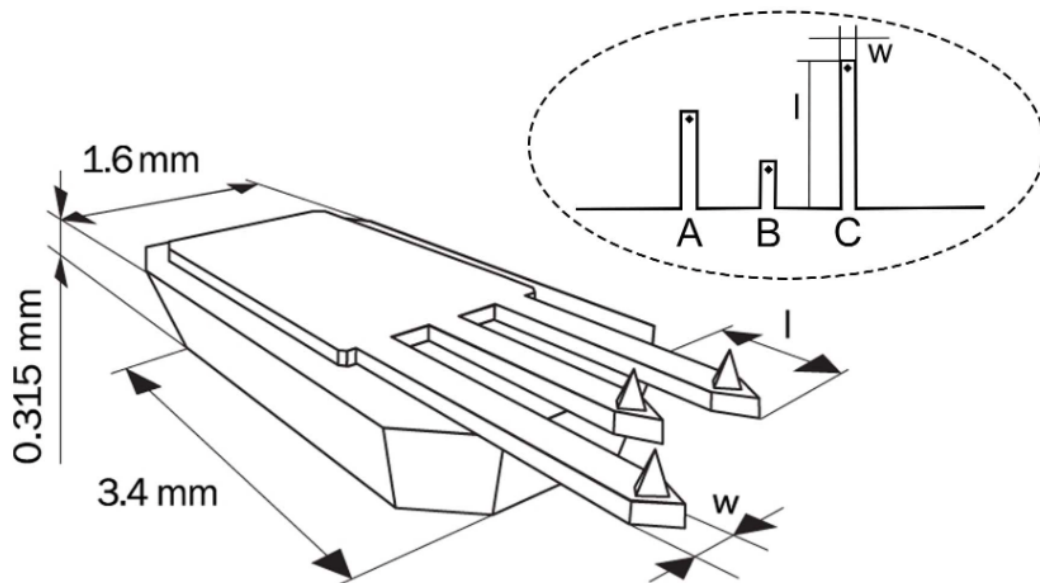
AFM Probe with 3 Different Soft Tapping Mode AFM Cantilevers

AFM probes of the HQ:NSC35 series have three different soft tapping mode AFM cantilevers on one side of the holder chip. They can be used in various applications.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

Coating

none



AFM Probe Specifications

AFM Tip

| SHAPE | HEIGHT | FULL CONE ANGLE | RADIUS |
|---------|--|-----------------|--------|
| Rotated | 15 μm (12 – 18 μm)* | 40° | < 8 nm |

AFM Cantilever

| CANTILEVER | SHAPE | FORCE CONST. | RES. FREQ. | LENGTH | WIDTH | THICKNESS |
|--------------|-------|----------------------------|-----------------------------|--|---|--|
| Cantilever A | Beam | 8.9 N/m (2.7 – 24 N/m)* | 205 kHz (130 – 290 kHz)* | 110 μm (1 – 115 μm)* | 35 μm (32 – 38 μm)* | 2 μm (1.5 – 2.5 μm)* |
| Cantilever B | Beam | 16 N/m (4.8 – 44 N/m)* | 300 kHz (185 – 430 kHz)* | 90 μm (1 – 95 μm)* | 35 μm (32 – 38 μm)* | 2 μm (1.5 – 2.5 μm)* |
| Cantilever C | Beam | 5.4 N/m (1.7 – 14 N/m)* | 150 kHz (95 – 205 kHz)* | 130 μm (1 – 135 μm)* | 35 μm (32 – 38 μm)* | 2 μm (1.5 – 2.5 μm)* |

* typical values